

SNLS173B-SEPTEMBER 2004-REVISED NOVEMBER 2004

SCAN921821 Dual 18-Bit Serializer with Pre-emphasis, IEEE 1149.1 (JTAG), and At-Speed BIST

Check for Samples: SCAN921821

FEATURES

- 15-66 MHz Dual 18:1 Serializer with 2.376 Gbps **Total Throughput**
- 8-level Selectable Pre-emphasis on Each Channel Drives Lossy Cables and Backplanes
- >15kV HBM ESD Protection on Bus LVDS I/O Pins
- **Robust BLVDS Serial Data Transmission with Embedded Clock for Exceptional Noise** Immunity and Low EMI
- **Power Saving Control Pin for Each Channel**
- IEEE 1149.1 "JTAG" Compliant
- **At-Speed BIST PRBS Generation**
- No External Coding Required
- Internal PLL, No External PLL Components Required
- Single +3.3V Power Supply
- Low Power: 260 mW (typ) Per Channel at 66 MHz with PRBS-15 Pattern
- Single 3.3 V Supply
- **Fabricated with Advanced CMOS Process** Technology
- Industrial -40 to +85°C Temperature Range
- **Compact 100-ball NFBGA Package**

DESCRIPTION

The SCAN921821 is a dual channel 18-bit serializer featuring signal conditioning, boundary SCAN, and atspeed BIST. Each serializer block transforms an 18bit parallel LVCMOS/LVTTL data bus into a single Bus LVDS data stream with embedded clock. This single serial data stream with embedded clock simplifies PCB design and reduces PCB cost by narrowing data paths that in turn reduce PCB size and layers. The single serial data stream also reduces cable size, the number of connectors, and eliminates clock-to-data and data-to-data skew.

Each channel also has an 8-level selectable preemphasis feature that significantly extends performance over lossy interconnect. Each channel also has its own powerdown pin that saves power by reducing supply current when the channel is not being used.

The SCAN921821 also incorporates advanced testability features including IEEE 1149.1 and atspeed BIST PRBS pattern generation to facilitate verification of board and link integrity

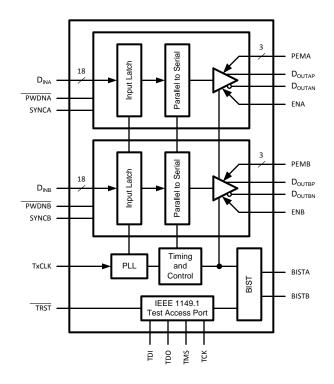


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Block Diagram





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings ⁽¹⁾⁽²⁾

	U				
Supply Voltage (V	(סמ		-0.3V to +4V		
Supply Voltage (V	_{DD}) Ramp Rate		< 30 V/ms		
LVCMOS/LVTTL Ir	nput Voltage		-0.3V to (V _{DD} +0.3V)		
LVCMOS/LVTTL C	Output Voltage		-0.3V to (V _{DD} +0.3V)		
Bus LVDS Driver C	Dutput Voltage		-0.3V to +3.9V		
Bus LVDS Output	Short Circuit Duration		10ms		
Junction Temperat	ure		+150°C		
Storage Temperatu	ıre		−65°C to +150°C		
Lead Temperatu	re (Soldering, 4 seconds)		+220°C		
Maximum Package	Power Dissipation at 25°C	NFBGA-100	3.57 W		
		Derating Above 25°C	28.57 mW/°C		
Thermal resistance	•	θ _{JA}	35°C/W		
		θ _{JC}	11.1°C/W		
ESD Rating	HBM, 1.5 KΩ, 100 pF	All pins	>8 kV		
		Bus LVDS pins	>15 kV		
	MM, 0Ω, 200 pF	ΜΜ, 0Ω, 200 pF			
	CDM		>2 kV		

(1) "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be specified. They are not meant to imply that the devices should be operated at these limits. The table of "Electrical Characteristics" specifies conditions of device operation.

(2) If Military/Aerospace specified devices are required, please contact the TI Sales Office/ Distributors for availability and specifications.



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Recommended Operating Conditions

	Min	Nom	Max	Units
Supply Voltage (V _{DD})	3.15	3.3	3.45	V
Operating Free Air Temperature (T _A)	-40	+25	+85	°C
Clock Rate	15		66	MHz
Supply Noise			100	mV p-p

DC Electrical Characteristics

Over recommended operating supply and temperature ranges unless otherwise specified.⁽¹⁾⁽²⁾

Symbol			Min	Тур	Max	Units
LVCMOS/L	VTTL Input DC Specification	ons				
V _{IH}	High Level Input Voltage		2.0		V _{DD}	V
V _{IL}	Low Level Input Voltage		GND		0.8	V
V _{CL}	Input Clamp Voltage	I _{CL} = −18 mA	-1.5	-0.7		V
I _{INH}	High Level Input Current	$V_{IN} = V_{DD} = V_{DDMAX}$	-20	±2	+20	μA
I _{INL}	Low Level Output Current	$V_{IN} = V_{SS}, V_{DD} = V_{DDMAX}$	-10	±2	+10	μA
1149.1 (JT/	AG) DC Specifications					
V _{IH}	High Level Input Voltage		2.0		V _{DD}	V
V _{IL}	Low Level Input Voltage		GND		0.8	V
V _{CL}	Input Clamp Voltage	I _{CL} = −18 mA	-1.5	-0.7		V
I _{INH}	High Level Input Current	$V_{IN} = V_{DD} = V_{DDMAX}$	-20		+20	μA
I _{INL}	Low Level Output Current	$V_{IN} = V_{SS}, V_{DD} = V_{DDMAX}$	-200		+200	μA
V _{OH}	High Level Output Voltage	I _{OH} = −9 mA	2.3		V _{DD}	mV
V _{OL}	Low Level Output Voltage	I _{OL} = 9 mA	GND		0.5	mV
I _{OS}	Output Short Circuit Current	V _{OUT} = 0 V	-100	-80	-50	mA
1	Output Tri-state	$\overline{\text{PWDN}}$ or EN = 0.8V, V _{OUT} = 0 V	-10		+10	μA
I _{OZ}	Current	$\overline{\text{PWDN}}$ or $\text{EN} = 0.8\text{V}$, $\text{V}_{\text{OUT}} = \text{VDD}$	-30		+30	μA
Bus LVDS	Output DC Specifications					
V _{OD}	Output Differential Voltage (DO+) - (DO-)	See Figure 10, $R_L = 100\Omega$	450	500	550	mV
ΔV_{OD}	Output Differential Voltage Unbalance			2	15	mV
V _{OS}	Offset Voltage		1.05	1.2	1.25	V
ΔV_{OS}	Offset Voltage Unbalance			2.7	15	mV

(1) Typical values are given for $V_{CC} = 3.3V$ and $T_A = +25^{\circ}C$. (2) Current into device pins is defined as positive. Current out of device pins is defined as negative. Voltages are referenced to ground except VOD, ΔVOD, VTH and VTL which are differential voltages.

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STRUMENTS

EXAS

DC Electrical Characteristics (continued)

Over recommended operating supply and temperature ranges unless otherwise specified.⁽¹⁾⁽²⁾

Symbol	Parameter	Cor	nditions	Min	Тур	Max	Units	
		Pre-Emph	1.10	1.24	1.35			
		Pre-Emph	asis Level = 2	1.35	1.47	1.55		
	Pre-Emphasis Output	Pre-Emph	asis Level = 3	1.55	1.70	1.80		
Q _{POV}	Voltage Ratio	Pre-Emph	asis Level = 4	1.80	1.91	1.95		
	V _{ODPRE} / V _{OD}	Pre-Emph	asis Level = 5	1.95	2.08	2.20		
		Pre-Emph	asis Level = 6	2.10	2.21	2.35		
		Pre-Emph	asis Level = 7	2.15	2.30	2.50		
I _{OS}	Output Short Circuit Current	DO = 0V, $Din = H$,	-10	-25	-75	mA		
	TRI-STATE Output	PWDN or EN =	-10	± 1	+10	μA		
Current		\overline{PWDN} or $EN =$	$0.8V, DO = VDD^{(3)}$	-55	± 6	+55	μA	
ower Sup	oply Current (DVDD, PVD	D and AVDD Pins)						
	Total Supply Current	C 45nF	f = 66 MHz, PRBS-15 Pattern		160	225	mA	
I _{DD}	Total Supply Current (includes load current)		f = 66 MHz, Worst Case Pattern (Checker-Board Pattern)		180		mA	
	Total Supply Current with Pre-Emphasis (includes load current)	Total Supply Current	C 1555	f = 66 MHz, PRBS-15 Pattern		240		mA
I _{DDP}		$C_L = 15 pF,$ $R_L = 100 \Omega$	f = 66 MHz, Worst Case Pattern (Checker-Board Pattern)		280	325	mA	
I _{DDX}	Supply Current Powerdown	PWDN = 0.8V, EN = 0.8V			1.0	3.0	mA	

(3) Ioz is measured at each pin. The DOUT pin not under test is floated to isolate the TRI-STATE current flow.

Timing Requirements for TCLK

Over recommended operating supply and temperature ranges unless otherwise specified.⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Units
t _{TCP}	Transmit Clock Period		15.2	Т	66.7	ns
t _{TCIH}	Transmit Clock High Time		0.4T	0.5T	0.6T	ns
t _{TCIL}	Transmit Clock Low Time		0.4T	0.5T	0.6T	ns
t _{CLKT}	TCLK Input Transition Time			3	6	ns
t _{JIT}	TCLK Input Jitter	See ⁽³⁾			80	ps (RMS)

(1)

Typical values are given for V_{CC} = 3.3V and T_A = +25°C. Current into device pins is defined as positive. Current out of device pins is defined as negative. Voltages are referenced to ground except VOD, Δ VOD, VTH and VTL which are differential voltages. Specified by design using statistical analysis. (2)

(3)



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AC Electrical Characteristics

Over recommended operating supply and temperature ranges unless otherwise specified. (1)(2)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Serializer A	AC Specifications					
t _{LLHT}	Bus LVDS Low-to-High Transition Time	See Figure 2, $^{(3)}$ R _L = 100Ω,		0.3	0.4	ns
t _{LHLT}	Bus LVDS High-to-Low Transition Time	$R_L = 100\Omega$, $C_L=10$ pF to GND		0.3	0.4	ns
t _{DIS}	DIN (0-17) Setup to TCLK	See Figure 4, ⁽³⁾	1.9			ns
t _{DIH}	DIN (0-17) Hold from TCLK	$R_L = 100\Omega$, $C_L=10pF$ to GND	0.6			ns
t _{HZD}	DO ± HIGH to TRI-STATE Delay			3.9	10	ns
t _{LZD}	DO ± LOW to TRI- STATE Delay	See Figure 5		3.5	10	ns
t _{ZHD}	DO ± TRI-STATE to HIGH Delay	$R_L = 100\Omega$, $C_L=10pF$ to GND		3.2	10	ns
t _{ZLD}	DO ± TRI-STATE to LOW Delay			2.4	10	ns
t _{SPW}	SYNC Pulse Width	See Figure 7, $R_L = 100\Omega$	5*t _{TCP}		6*t _{TCP}	ns
t _{PLD}	Serializer PLL Lock Time	See Figure 6, $R_L = 100\Omega$	510*t _{TCP}		1024*t _{TCP}	ns
t _{SD}	Serializer Delay	See Figure 8 , $R_L = 100\Omega$	t _{TCP} + 2.5	t _{TCP} + 4.5	t _{TCP} + 6.5	ns
t _{SKCC}	Channel to Channel Skew			70		ps
t _{RJIT}	Random Jitter	Room Temperature, V _{DD} = 3.3V, 66 MHz		6.1		ps (RMS)
+	Deterministic Jitter	15 MHz	-390		320	ps
t _{DJIT}	Figure 9, ⁽³⁾	66 MHz	-60		30	ps
1149.1 (JT	AG) AC Specifications					
f _{MAX}	Maximum TCK Clock Frequency		25			MHz
t _S	TDI or TMS Setup to TCK, H or L		2.4			ns
t _H	TDI or TMS Hold from TCK, H or L	C _L = 15pF,	2.8			ns
t _{W1}	TCK Pulse Width, H or L	$R_L = 500 \Omega$	10			ns
t _{W2}	TRST Pulse Width, L		10			ns
t _{REC}	Recovery Time, TRST to TCK		2			ns

(1)

Typical values are given for $V_{CC} = 3.3V$ and $T_A = +25^{\circ}C$. Current into device pins is defined as positive. Current out of device pins is defined as negative. Voltages are referenced to ground except VOD, Δ VOD, VTH and VTL which are differential voltages. Specified by design using statistical analysis. (2)

(3)



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AC Timing Diagrams and Test Circuits

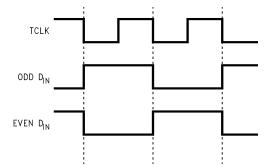


Figure 1. "Worst Case" Serializer IDD Test Pattern

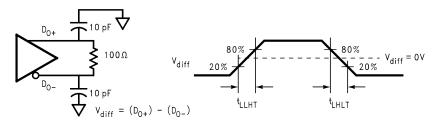


Figure 2. Serializer Bus LVDS Distributed Output Load and Transition Times

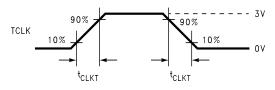


Figure 3. Serializer Input Clock Transition Time

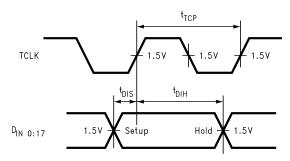
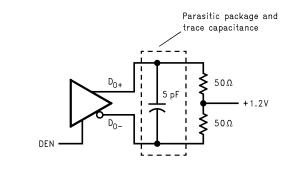


Figure 4. Serializer Setup/Hold Times



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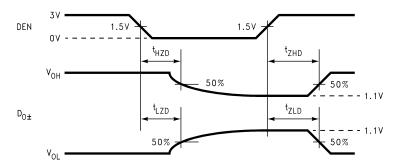


Figure 5. Serializer TRI-STATE Test Circuit and Timing

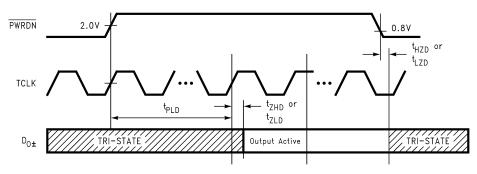


Figure 6. Serializer PLL Lock Time, and PWRDN TRI-STATE Delays

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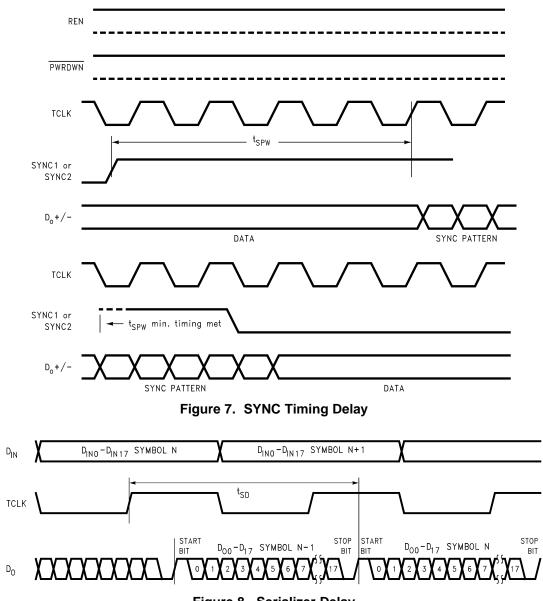


Figure 8. Serializer Delay





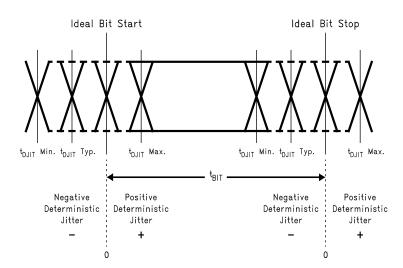
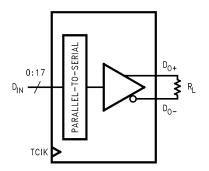


Figure 9. Deterministic Jitter and Ideal Bit Position



 V_{OD} = (DO⁺)–(DO⁻). Differential output signal is shown as (DO+)–(DO-), device in Data Transfer mode.

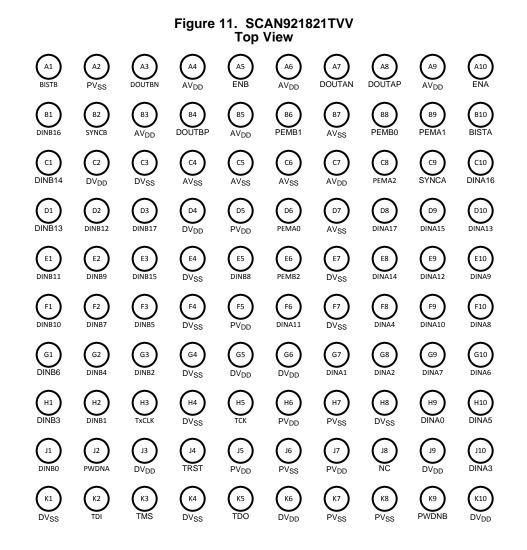
Figure 10. V_{OD} Diagram

Pre-emphasis Truth Table

PEM LEVEL	PEM2	PEM1	PEM0
0	L	L	L
1	L	L	Н
2	L	Н	L
3	L	Н	Н
4	Н	L	L
5	Н	L	Н
6	Н	Н	L
7	Н	Н	Н



Pin Diagram





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Pin Descriptions										
Pin Name	Pin Count	I/O, Type	Description							
DATA PINS		1								
DINA0-17	18		Transmitter inputs. There is a pull-down circuitry on each of these pins which are active							
DINB0-17	18	I, LVCMOS	if respective PWDNA or PWDNB pin is pulled high.							
DOUTAP	1									
DOUTAN	1	O,BLVDS	Inverting and non-inverting differential transmitter outputs.							
DOUTBP	1	O,BLVD3	inverting and non-inverting differential transmitter outputs.							
DOUTAN	1									
TIMING AND CO	ONTROL PINS									
TxCLK	1	I, LVCMOS	Transmitter reference clock. Used to strobe data at the inputs and to drive the transmitter PLL. There is a pull-up circuitry on this pin which is always active.							
ENA	1		Transmitter outputs enable pins. There is a pull-down circuitry on each of these pins that							
ENB	1	I, LVCMOS	are active if corresponding PWDNA or PWDNB pin is pulled high. When these pins are set to LOW, the transmitter outputs will be disabled. The PLL will remain locked.							
PWDNA	1	I, LVCMOS	Stand-by mode pins. There is a pull-down circuitry on each of these pins that are always active. When these pins are set to LOW, the transmitter will be put in low power mode							
PWDNB	1		and the PLL will lose lock.							
SYNCA	1		Transmitter synchronization pins. There is a pull-down circuitry on each of these pins							
SYNCB	1	I, LVCMOS	that are active if corresponding PWDNA or PWDNB pin is pulled high. When these pins are set to HIGH, the transmitter will ignore incoming data and send SYNC patterns to provide a locking reference to receiver(s).							
PRE-EMPHASIS	PINS	ł								
PEMA0-2	3	1.1.1/01/00	8-level pre-emphasis selection pins. There is a pull-down circuitry on each of these pins							
PEMB0-2	3	I, LVCMOS	which are active if corresponding PWDNA or PWDNB pin is pulled high.							
JTAG PINS										
TDI	1	I, LVCMOS	Test Data Input to support IEEE 1149.1. There is a pull-up circuitry on this pin which is always active.							
TDO	1	O, LVCMOS	Test Data Output to support IEEE 1149.1.							
TMS	1	I, LVCMOS	Test Mode Select Input to support IEEE 1149.1. There is a pull-up circuitry on this pin which is always active.							
ТСК	1	I, LVCMOS	Test Clock Input to support IEEE 1149.1. There is no failsafe circuitry on this pin.							
TRST	1	I, LVCMOS	Test Reset Input to support IEEE 1149.1. There is a pull-up circuitry on this pin which is always active.							
BIST PINS										
BISTA	1		BIST selection pins. These pins select which transmitter will generate a PRBS like data.							
BISTB	1	I, LVCMOS	There is a pull-down circuitry on these pins which are active if corresponding PWDNA or PWDNB pin is pulled high.							
POWER PINS		T								
AVDD	6	I, POWER	Power Supply for the LVDS circuitry.							
DVDD	8	I, POWER	Power Supply for the digital circuitry.							
PVDD	5	I, POWER	Power Supply for the PLL and BG circuitry.							
AVSS	5	I, POWER	Ground reference for the LVDS circuitry.							
DVSS	10	I, POWER	Ground reference for the digital circuitry.							
PVSS	5	I, POWER	Ground reference for the PLL and BG circuitry.							
OTHER PINS										
NC	1	N/A	Not connected.							



9-Mar-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Drawing			(2)		(3)		(4)	
SCAN921821TSM	ACTIVE	NFBGA	NZD	100	240	TBD	Call TI	Call TI	-40 to 85	SCAN921821 TSM	Samples
SCAN921821TSM/NOPB	ACTIVE	NFBGA	NZD	100	240	Green (RoHS & no Sb/Br)	SNAGCU	Level-4-260C-72 HR	-40 to 85	SCAN921821 TSM	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

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⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

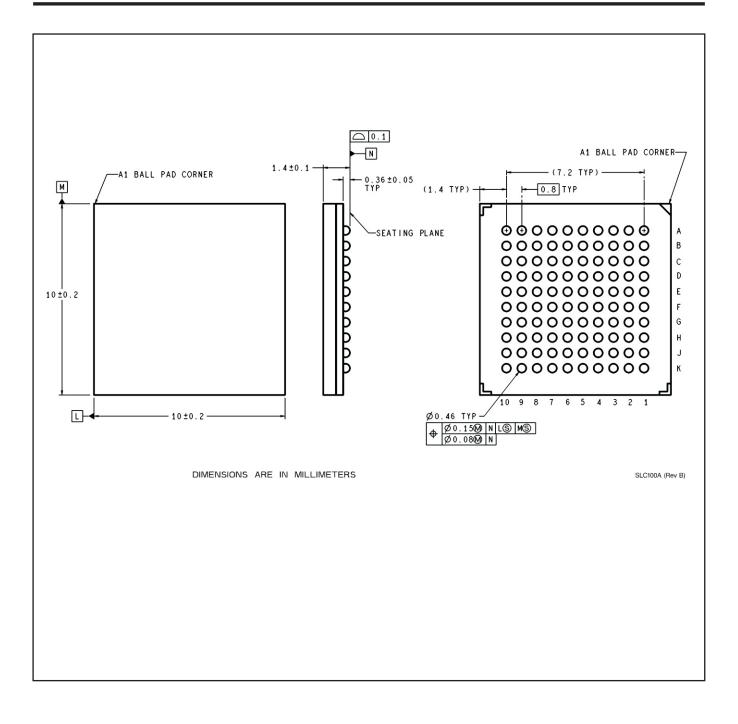
⁽⁴⁾ Only one of markings shown within the brackets will appear on the physical device.

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MECHANICAL DATA

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Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
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